

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/683,837	FUNKE ET AL.	
Examiner		Michael D Masinick	Art Unit	Page 1 of 1

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages
	U	"Capacity Planning Model: The Important Inputs, Formulas, and Benefits" - Thomas J. Occhino, White Oak Semiconductor, IEEE 2000.
	V	"Evaluation of Capacity Planning Practices for the Semiconductor Industry" -Metin Cakanyildirim et al. August 2002. IEEE.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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